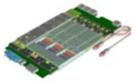
V93000 Smart Scale

Setting The Standard in Test

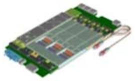
Introducing …

- **The Only ATE** to provide **Superior Test Economics** with the Highest Resource Parallelism in the Smallest Infrastructure by **applying Moore's Law to Test.**
- **The First ATE** to deliver **high integration and high performance** as standard with precision DC, 1.6Gbps digital I/O and 8Gbps high speed enabled by Verigy's per pin technology.
- **The First ATE** to address the next level of silicon integration by applying **Smart Test Methodologies** such as System-Like-Stress-Test, site independent test and performance test at probe.
- **The Broadest ATE device coverage** to scale from new entry level digital and mixed-signal solutions to massive multi-site RF-SOC solutions by offering compatible tester configuration classes.

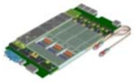
V93000 Smart Scale



Pin Scale 1600
(128 pins at 1.6G)
2x Speed; 2x Memory
2x Density

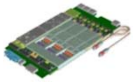


Pin Scale 1600-ME
(64 pins at 1.6G)
2x Speed 2x Memory
+ Memory Emulation

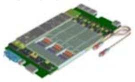


Pin Scale 9G
(64 pins at >8G)
>2x Speed, 2x Density
2x Memory

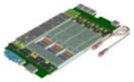
Multi-site DPS



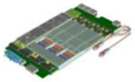
DC Scale DPS32



DC Scale VI32



DC Scale UHC4



MBAV8+

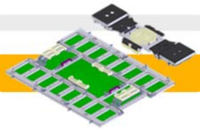
LTE Advanced,
802.11ac, WiMAX,
Zero Overhead Upload

Port Scale RF

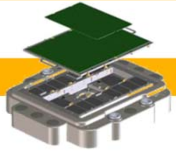
Source

FE12 / FE24

Pure Clock



Direct-Probe™



Same DUT Interface

V93000-L

V93000-S

V93000-C

V93000-A

SmarTest + Libraries + Test Programs + InstaPin™ Licensing

Clock-Domain per Pin, Precision PMU per Pin, System-Like Stress Test

More information:

Smart Scale Press Release

And watch for the new Smart Scale video coming soon on Verigy.com